

**Search Notes**

Application/Control No.

10/016,096

Examiner

Christopher L. Lavin

Applicant(s)/Patent under  
Reexamination

WEI ET AL.

Art Unit

2621

**SEARCHED**

Class	Subclass	Date	Examiner

**INTERFERENCE SEARCHED**

Class	Subclass	Date	Examiner
See Interference Search Printout			

**SEARCH NOTES  
(INCLUDING SEARCH STRATEGY)**

	DATE	EXMR
Updated East Search	11/1/2005	CLL
Interference Search History Printout	11/1/2005	CLL